

First Named Inventor	Leonard Forbes
Serial No.	10/719,772
Filing Date	November 21, 2003
Group Art Unit	2815
Examiner Name	Unknown
Confirmation No.	2900
Attorney Docket No.	400.252US01
Title: APPARATUS AND METHOD FOR SPLIT GATE NROM MEMORY	

JFN

GENERAL TRANSMITTAL FORM UNDER 37 CFR 1.8 (LARGE ENTITY)

Mail Stop Amendment
Commissioner for Patents
P. O. Box 1450
Alexandria, VA 22313-1450

Enclosures

The following documents are enclosed:

Information Disclosure Statement (1 pg.); Form 1449 (7 pgs.); 62 copies of cited references; U.S. reference(s) not included pursuant to 37 C.F.R. 1.98 (c)(2)(i);
 An itemized return-receipt postcard

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Submitted By

Name	Kenneth W. Bolvin	Reg. No.	34,125	Telephone	(612) 312-2211
Signature				Date	5/18/04

Certificate of Mailing

I certify that this correspondence and the identified documents listed on this transmittal are being deposited with the United States Postal Service with sufficient postage as first class mail in an envelope addressed to: Mail Stop Amendment, Commissioner for Patents, P. O. Box 1450, Alexandria, VA 22313-1450 on May 18, 2004.

Name	Rhonda L. Foley	Signature	
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(LARGE ENTITY TRANSMITTAL UNDER 37 CFR § 1.8)



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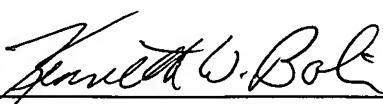
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In compliance with 37 C.F.R. §§ 1.56 and 1.97, *et seq.*, the enclosed materials are brought to the attention of the Examiner for consideration in connection with the above-identified Application. Pursuant to 37 C.F.R. 1.98 (a)(2)(i), as this application was filed after June 30, 2003, Applicant has not included copies of U.S. Patents or U.S. Patent Applications. Applicant respectfully requests that this Information Disclosure Statement be entered and the references listed on the attached Form 1449 be considered by the Examiner and made of record. Pursuant to MPEP §609, Applicant further requests that the Examiner initial next to each reference on the Form 1449 to indicate that the listed references have been considered. Applicant further requests that a copy of the initialed Form 1449 be returned with the next official communication.

As an Office Action has not yet issued in this application, Applicant believes that no fees are due. However, the Commissioner for Patents is hereby authorized to charge any additional fees to Deposit Account No. 501373. If the Examiner has any questions or concerns regarding this application, please contact the undersigned at (612) 312-2211.

Respectfully submitted,

Date: 3/18/04


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U.S. Patent References				
Examiner Initials	Document No.	Issue/Publication Date	Name	Filing Date
	2001/0001075 A1	05/10/2001	Ngo	12/20/2000
	2001/0004332 A1	06/21/2001	Eitan	02/07/2001
	2001/0011755 A1	08/09/2001	Tasaka	09/16/1998
	2001/0022375 A1	09/20/2001	Hsieh	02/06/2001
	2002/0130356 A1	09/19/2002	Sung	05/16/2002
	2002/0142569 A1	10/03/2002	Chang	03/29/2001
	2002/0146885 A1	10/10/2002	Chen	04/03/2002
	2002/0151138 A1	10/17/2002	Liu	04/10/2002
	2002/0177275 A1	11/28/2002	Liu	05/28/2002
	2002/0182829 A1	12/05/2002	Chen	05/31/2001
	2003/0057997 A1	03/27/2003	Sun	10/18/2002
	2003/0067807 A1	04/10/2003	Lin	10/22/2001
	2003/0113969 A1	06/19/2003	Cho	10/22/2002
	2003/0117861 A1	06/26/2003	Maayan	12/20/2001
	4,184,207	01/15/1980	McElroy	07/12/1978
	4,420,504	12/13/1983	Cooper	05/17/1982
	4,755,864	07/05/1998	Ariizumi	09/14/1987
	4,881,114	11/14/1989	Mohsen	05/16/1986
	5,241,496	08/31/1993	Lowrey	08/19/1991
	5,330,930	07/19/1994	Chi	12/31/1992
	5,378,647	01/03/1995	Hong	10/25/1993
	5,379,253	01/03/1995	Bergemont	06/01/1992
	5,397,725	03/14/1995	Wolstenholme	10/28/1993
	5,467,305	11/14/1995	Bertin	03/12/1992
	5,576,236	11/19/1996	Chang	06/28/1995
	5,768,192	06/16/1998	Eitan	07/23/1996
	5,792,697	08/11/1998	Wen	04/23/1997
	5,858,841	01/12/1999	Hsu	11/25/1997
	5,911,106	06/08/1999	Tasaka	08/29/1997
	5,936,274	08/10/1999	Forbes	07/08/1997
	5,946,558	08/31/1999	Hsu	05/30/1997
	5,966,603	10/12/1999	Eitan	06/11/1997
	5,994,745	11/30/1999	Hong	04/24/1995
	6,011,725	01/04/2000	Eitan	02/04/1999
	6,028,342	02/22/2000	Chang	02/11/1998
	6,030,871	02/29/2000	Eitan	05/05/1998
	6,044,022	03/28/2000	Nachumovsky	02/26/1999
	6,081,456	06/27/2000	Dadashev	02/04/1999
	6,108,240	08/22/2000	Lavi	02/04/1999

Examiner Signature	Date Considered
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STATEMENT
FORM PTO-1449**

6,133,102	10/17/2000	Wu	06/19/1998
6,134,156	10/17/2000	Eitan	02/02/1999
6,143,636	11/07/2000	Forbes	08/20/1998
6,147,904	11/14/2000	Liron	02/04/1999
6,157,570	12/05/2000	Nachumovsky	02/04/1999
6,172,396 B1	01/09/2001	Chang	04/23/1998
6,174,758 B1	01/16/2001	Nachumovsky	03/03/1999
6,175,523 B1	01/16/2001	Yang	10/25/1999
6,181,597 B1	01/30/2001	Nachumovsky	02/04/1999
6,184,089 B1	02/06/2001	Chang	01/27/1999
6,201,282 B1	03/13/2001	Eitan	12/23/1999
6,201,737 B1	03/13/2001	Hollmer	04/26/2000
6,204,529 B1	03/20/2001	Lung	08/27/1999
6,207,504 B1	03/27/2001	Hsieh	12/30/1998
6,208,164 B1	03/27/2001	Noble	08/04/1998
6,208,557 B1	03/27/2001	Bergemont	05/21/1999
6,215,702 B1	04/10/2001	Derhacobian	02/16/2000
6,218,695 B1	04/17/2001	Nachumovsky	06/28/1999
6,222,768 B1	04/24/2001	Hollmer	04/26/2000
6,238,976 B1	05/29/2001	Noble	02/27/1998
6,240,020 B1	05/29/2001	Yang	10/25/1999
6,243,300 B1	06/05/2001	Sunkavalli	02/16/2000
6,249,460 B1	06/19/2001	Forbes	02/28/2000
6,251,731 B1	06/26/2001	Wu	07/13/1999
6,255,166 B1	07/03/2001	Ogura	12/28/1999
6,256,231 B1	07/03/2001	Lavi	02/04/1999
6,266,281 B1	07/24/2001	Derhacobian	02/16/2000
6,269,023 B1	07/31/2001	Derhacobian	10/23/2000
6,272,043 B1	08/07/2001	Hollmer	06/23/2000
6,275,414 B1	08/14/2001	Randolph	11/22/2000
6,282,118 B1	08/28/2001	Lung	10/06/2000
6,291,854 B1	09/18/2001	Peng	12/30/1999
6,297,096 B1	10/02/2001	Boaz	07/30/1999
6,303,436 B1	10/16/2001	Sung	09/21/1999
6,327,174 B1	12/04/2001	Jung	02/24/2000
6,337,808 B1	01/08/2002	Forbes	08/30/1999
6,348,711 B1	02/19/2002	Eitan	10/06/1999
6,383,871 B1	05/07/2002	Noble	08/31/1999
6,384,448 B1	05/07/2002	Forbes	02/28/2000
6,392,930 B2	05/21/2002	Jung	01/09/2001
6,417,049 B1	07/09/2002	Sung	02/01/2000
6,417,053 B1	07/09/2002	Kuo	11/20/2001

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6,421,275 B1	07/16/2002	Chen	01/22/2002
6,424,001 B1	07/23/2002	Forbes	02/09/2001
6,429,063 B1	08/06/2002	Eitan	03/06/2000
6,432,778 B1	08/13/2002	Lai	08/07/2001
6,436,764 B1	08/20/2002	Hsieh	06/08/2000
6,461,949 B1	10/08/2002	Chang	03/29/2001
6,468,864 B1	10/22/2002	Sung	08/10/2001
6,469,342 B1	10/22/2002	Kuo	11/20/2001
6,477,084 B2	11/05/2002	Eitan	02/07/2001
6,486,028 B1	11/26/2002	Chang	11/20/2001
6,487,050 B1	11/26/2002	Liu	12/28/1999
6,496,034 B2	12/17/2002	Forbes	02/09/2001
6,498,377 B1	12/24/2002	Lin	03/21/2002
6,514,831 B1	02/04/2003	Liu	11/14/2001
6,531,887 B2	03/11/2003	Sun	06/01/2001
6,545,309 B1	04/08/2003	Kuo	03/22/2002
6,552,287 B1	04/22/2003	Eitan	12/14/1998
6,559,013 B1	05/06/2003	Pan	07/10/2002
6,576,511 B2	06/10/2003	Pan	05/02/2001
6,580,135 B2	06/17/2003	Chen	03/22/2002
6,580,630 B1	06/17/2003	Liu	06/07/2002
6,597,037 B1	07/22/2003	Forbes	09/26/2000
6,602,805 B2	08/05/2003	Chang	12/14/2000
6,607,957 B1	08/19/2003	Fan	07/31/2002
6,610,586 B1	08/26/2003	Liu	09/04/2002
6,613,632 B2	09/02/2003	Liu	05/28/2002
6,617,204 B2	09/09/2003	Sung	08/13/2001
6,639,268 B2	10/28/2003	Forbes	05/20/2002

Foreign Patent References				
Examiner Initials	Foreign Patent		Name	Publication Date
	Country	No.		
	EP	84303740.9	American Microsystems, Inc.	01/25/1985
	EP	90115805.5	Kabushiki Kaisha Toshiba	02/20/1991
	EP	01113179.4	Infineon Technologies AG	12/04/2002

Other References	
Examiner Initials	Author, Title, Date, Pages, etc.

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Title: APPARATUS AND METHOD FOR SPLIT GATE NROM MEMORY		Sheet 4 of 7

	B. Eitan et al., "Characterization of Channel Hot Electron Injection by the Subthreshold Slope of NROM™ Device," IEEE Electron Device Lett., Vol. 22, No. 11, (Nov. 2001) pp. 556-558, Copyright 2001 IEEE.
	B. Eitan et al., "Spatial Characterization of Hot Carriers Injected into the Gate Dielectric Stack of a MOFSET Based on Non-Volatile Memory Device," date unknown, pp. 58-60.
	B. Eitan et al., "NROM: A Novel Localized Trapping, 2-Bit Nonvolatile Memory Cell," IEEE Electron Device Lett., Vol. 21, No. 11, (Nov. 2000), pp. 543-545, Copyright 2000 IEEE.
	E. Maayan et al., "A 512Mb NROM Flash Data Storage Memory with 8MB/s Data Range," Dig. IEEE Int. Solid-State Circuits Conf., San Francisco, (Feb 2002), pp. 1-8, Copyright Saifun Semiconductors Ltd. 2002.
	E. Maayan et al., "A 512Mb NROM Flash Data Storage Memory with 8MB/s Data Range," ISSCC 2002 Visuals Supplement, Session 6, SRAM and Non-Volatile Memories, 6.1 and 6.2, pp. 76-77, 407-408. Copyright 1990 IEEE.
	M. Janai, "Data Retention, Endurance and Acceleration Factors of NROM Devices," IEEE 41 st Annual International Reliability Physics Symposium, Dallas, TX (2003), pp. 502-505, Copyright 1989 IEEE.
	S. Minami and Y. Kamigaki, "A Novel MONOS Nonvolatile Memory Device Ensuring 10-Year Data Retention after 10 ⁷ Erase/Write Cycles," IEEE Transactions on Electron Devices, Vol. 40, No. 11 (Nov. 1993) pp. 2011-2017, Copyright 1998 IEEE.
	C. Pan, K. Wu, P. Freiberger, A. Chatterjee, G. Sery, "A Scaling Methodology for Oxide-Nitride-Oxide Interpoly Dielectric for EPROM Applications," IEEE Transactions on Electron Devices, Vol. 37, No. 6, (June 1990), pp. 1439-1443, Copyright 1990 IEEE.
	P. Manos and C. Hart, "A Self-Aligned EPROM Structure with Superior Data Retention," IEEE Electron Device Letters, Vol. 11, No. 7, (July 1990) pp. 309-311, Copyright 1990 IEEE
	W. Owen and W. Tchon, "E ² PROM Product Issues and Technology Trends," IEEE 1989, pp. 17-19, Copyright 1989 IEEE.
	T. Huang, F. Jong, T. Chao, H. Lin, L. Leu, K. Young, C. Lin, K. Chiu, "Improving Radiation Hardness of EEPROM/Flash Cell BY N ₂ O Annealing," IEEE Electron Device Letters, Vol. 19, No. 7 (July 1998), pp. 256-258, Copyright 1998 IEEE.
	B. Eitan et al., "Electrons Retention Model for Localized Charge in Oxide -Nitride-Oxide (ONO) Dielectric," IEEE Device Lett., Vol. 23, No. 9, (Sept. 2002), pp.556-558. Copyright 2002 IEEE.
	T. Nozaki, T. Tanaka, Y. Kijiya, E. Kinoshita, T. Tsuchiya, Y. Hayashi, "A 1-Mb EEPROM with MONOS Memory Cell for Semiconductor Disk Application," IEEE Journal of Solid-State Circuits, Vol. 26, No. 4 (April 1991), pp. 497-501, Copyright 1991 IEEE.
	F. Vollebregt, R. Cuppens, F. Druyts, G. Lemmen, F. Verberne, J. Solo, "A New E(E)PROM Technology With A TiSi ₂ Control Gate," IEEE 1989, pp. 25.8.1 – 25.8.4, Copyright 1989 IEEE.

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STATEMENT
FORM PTO-1449**

Sheet 5 of 7

	B. Eitan et al., "Impact of Programming Charge Distribution on Threshold Voltage and Subthreshold Slope of NROM Memory cells," IEEE Transactions on Electron Devices, Vol. 49, No. 11, (Nov. 2002), pp. 1939-1946, Copyright 2002 IEEE.
	B. Eitan et al., "Spatial characterization of Channel hot electron injection utilizing subthreshold slope of the localized charge storage NROM™ memory device," Non-Volatile Semiconductor Memory Workshop (NVSMW), Monterey, CA, (Aug. 2001), pp. 1-2.
	B. Eitan et al., "Can NROM, a 2-bit, Trapping Storage NVM Cell, Give a Real Challenge to Floating Gate Cells?" Int. Conf. on Solid State Devices and Materials, Tokyo, (1999), pp. 1-3, Copyright 1999 Saifun Semiconductors Ltd.
	S. Ogura, et al. "Twin MONOS Cell with Dual Control Gates," Halo LSI and New Halo, pp 187 –187.3, Date Unknown.
	T. Sugizaki, et al. "New 2-bit/Tr MONOS Type Flash Memory using Al ₂ O ₃ as Charge Trapping Layer," Fujitsu Laboratories Ltd, Date Unknown.
	T. Saito, et al. "Hot Hole Erase Characteristics and Reliability in Twin MONOS Device" Halo LSI, Date Unknown.
	Saifun Semiconductors, LTD. PowerPoint Presentation, Date Unknown
	Y. Roizin, et al. "Novel Techniques for data retention and Leff measurements in two bit MicroFlash® Memory Cells," Characterization and Metrology for ULSI Technology: 200 International Conf., pp. 181-185, Copyright 2001 American Institute of Physics, 1-56396-967-X/01.
	W. J. Tsai, et al. "Cause of Data Retention Loss in a Nitride-Based Localized Trapping Storage Flash Memory Cell," IEEE 40 th Annual International Reliability Physics Symposium, Dallas, (2002), pp. 34-38. Copyright 2002 IEEE.
	W.J. Tsai, et al. "Data Retention Behavior of a SONOS Type Two-Bit Storage Flash Memory Cell," IEDM 01-0179-01-722, Copyright 2001 IEEE.
	A. Shappir, et al., "Subthreshold slope degradation model for localized-charge-trapping based non-volatile memory devices," Solid-State Electronics 47 (2003), pp. 937-941. Copyright 2003 Elsevier Science Ltd.
	R. Neale, "AMD's MirrorBit – a big step in Flash progress," Electronic Engineering Design, V. 74, No. 906, pp. 47-50.
	I. Bloom, et al., "NROM™ -a new technology for non-volatile memory products" Solid-State Electronics 46 (2002), pp. 1757-1763. Copyright 2002 Elsevier Science Ltd.
	J. Bu and M. White, "Electrical characterization on ONO triple dielectric in SONOS nonvolatile memory devices," Solid-State Electronics 45 (2001) pp. 47-51. Copyright 2001 Elsevier Science Ltd.
	Y. Kamigaki and S. Minami, "MNOS Nonvolatile Semiconductor Memory Technology: Present and Future," IEICE Trans. Electron, Vol. E84-C, No. 6, pp. 713-723 (June 2001)

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--------------------	-----------------

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Title: APPARATUS AND METHOD FOR SPLIT GATE NROM MEMORY		Sheet 6 of 7

	E. Lusky, et al., "Electron Discharge Model of Locally-Trapped Charge in Oxide-Nitride-Oxide (ONO) Gates for NROM™ Non-Volatile Semiconductor Memory Devices," Extended Abstracts of the 2001 International Conference on Solid State Devices and Materials, Tokyo, 2001 pp. 534-535.
	A. Nughin, "n-Channel 256kb and 1Mb EEPROMs," ISSCC91, Session 134, Special Session on Technology in the USSR, Paper 13.4, 1991 IEEE International Solid State Circuits Conference, Digest of Technical Papers, pp. 228-229, 319
	G. Xue, et al., "Low Voltage Low Cost Nitride Embedded Flash Memory Cell" IMEC., Date Unknown.
	L. Breuil, et al., "A new 2 isolated-bits/cell flash memory device with self aligned split gate structure using ONO stacks for charge storage," IMEC, Date Unknown.
	J. Willer, et al., "UMEM: A U-shape Non-Volatile-Memory Cell," Ingentix GmbH & Co. KG., Infineon Technologies and Saifun Semiconductors, Date Unknown
	S. Kang, et al., "A Study of SONOS Nonvolatile Memory Cell Controlled Structurally by Localizing Charge-Trapping Layer," Samsung Electronics Co., Ltd., Date Unknown.
	Y. Roizin, et al., "In-Process Charging in <i>microFLASH®</i> Memory Cells," Tower Semiconductor, Ltd., Date Unknown
	A. Shappir, et al., "Subthreshold slope degradation model for localized-charge-trapping based non-volatile memory devices," Solid State Electronics, 47 (2003) pp. 937-941, Copyright 2003 Elsevier Science Ltd.
	I. Fujiwara, et al., "High speed program/erase sub 100 nm MONOS memory cell," Sony Corporation, Date Unknown
	E. Lusky, et al., "Investigation of Spatial Distribution of CHE Injection Utilizing the Subthreshold Slope and the Gate Induced Drain Leakage (GIDL) Characteristics of the NROM™ Device," Saifun Semiconductors, Ltd. and Tel Aviv University, Dept of Physical Electronics, pp. 1-2., Date Unknown
	C. C. Yeh, et al., "A Modified Read Scheme to Improve Read Disturb and Second Bit Effect in a Scaled MXVAND Flash Memory Cell," Macronix International Co., Ltd. and Department of Electronics Engineering, National Chiao-Tung University, Date Unknown.
	Y. K. Lee, et al., "30-nm Twin Silicon-Oxide-Nitride-Oxide-Silicon (SONOS) Memory (TSM) with High Erase Speed and Reliability," School of Electrical Engineering, Seoul National University, C&M, System LSI, ATD, PD, Samsung Electronics Co., Date Unknown
	J. H. Kim, et al., "Highly Manufacturable SONOS Non-Volatile Memory for the Embedded SoC Solution," 2003 Symposium on VLSI Technology Digest of Technical Papers, pp. 31-32.
	Y. Hayashi, et al., "Twin MONOS Cell with Dual Control Gates," 2000 Symposium on VLSI Technology Digest of Technical Papers, 2000 IEEE, pp. 122-123.
	M. K. Cho and D. M. Kim, "High Performance SONOS Memory Cells Free of Drain Turn-On and Over-Erase: Compatibility Issue with Current Flash Technology," IEEE Electron Device Letters, Vol. 21, No. 8, August 2000, pp. 399-401, Copyright 2000 IEEE

Examiner Signature		Date Considered	
--------------------	--	-----------------	--

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STATEMENT
FORM PTO-1449**

Sheet 7 of 7

	T. Y. Chan, K.K. Young and C. Hu, "A True Single-Transistor Oxide-Nitride-Oxide EEPROM Device," IEEE Electron Device Letters, Vol. EDL-8, No. 3, March 1987, pp. 93-95., Copyright 1987 IEEE.
	I. Bloom, et al., "NROM™ NVM technology for Multi-Media Applications," Saifun Semiconductors, Ltd. Ingentix, Ltd. and Infineon Technologies, Date Unknown
	E. J. Prinz, et al., "An Embedded 90nm SONOS Flash EEPROM Utilizing Hot Electron Injection Programming and 2-Sided Hot Hole Injection Erase," Motorola Embedded Memory Center, Date Unknown
	Y. Roizin, et al., "Retention Characteristics of <i>microFLASH</i> ® Memory (Activation Energy of Traps in the ONO Stack)," Tower Semiconductor, Ltd., Date Unknown
	Y. Roizin, et al., "Activation Energy of Traps in the ONO Stack of <i>microFLASH</i> ® Memory Cells," Tower Semiconductor, Ltd., Date Unknown
	Y. Roizin, et al., "'Dummy' Gox for Optimization of <i>microFLASH</i> ® Technology," Tower Semiconductor, Ltd., Date Unknown
	Y. K. Lee, et al., "Multi-Level Vertical Channel SONOS Nonvolatile Memory on SOI," 2002 Symposium on VLSI Technology Digest of Technical Papers, Copyright 2002 IEEE.
	T. Saito, et al., "CHE Program Behavior in MONOS Device," Halo LSI., Date Unknown
	J. Bu, et al., "Retention Reliability Enhanced SONOS NVSM with Scaled Programming Voltage," Microelectronics Lab., Date Unknown
	H. Tomiye, et al., "A novel 2-bit/cell MONOS memory device with a wrapped-control-gate structure that applies source-side hot-electron injection," 2002 Symposium on VLSI Technology Digest of Technical Papers, Copyright 2002 IEEE.
	Certified Translation, "Flash cell that seeks to replace current technology introduced enabling both low cost and high performance" Nikkei Microdevices, November 1999, pp. 147-148.
	Cappelletti, P., et al., "Failure mechanisms of Flash Cell in Program/Erase Cycling", IEEE, 1994, IEDM-94, pp. 291-294.
	Guan Huinan, et al., "On Scaling of SST Split-Gate Flash Memory Technologies", Department of Electrical and Computer Engineering, University of California, Irvine, Final Report 1998-1999 for MICRO Project 98-080.
	Pavan, Paolo, et al., "Flash Memory Cells – An Overview", Proceedings of the IEEE, Vol. 85, No. 8, August 1997, pp. 1248-1271.
	Seo, Jin-ho, et al., "Charge –to-Breakdown Characteristics of Thin Gate Oxide and Buried Oxide on SIMOX SOI Wafers", Journal of the Electrochemical Society, Vol. 144, No. 1, January 1997, pp. 375-378.

Examiner Signature		Date Considered	
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*Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.